

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	548	117/2.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 08:51
L2	468	117/3.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 09:13
L3	260	117/14.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 10:02
L5	1197	(large or high) near (resistance or resistivity) near4 (silicon or si) near (substrate or wafer)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 11:14
L6	60	(large or high) near (resistance or resistivity) near4 (silicon or si) near (substrate or wafer) and (bmd or oxygen near2 precipitat\$3 or bulk adj microdefect or bulk adj micro adj defect)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 11:33

## EAST Search History

L7	62	("20010032581"   "20020170631"   "20020179006"   "20030022003"   "20030051656"   "20030068890"   "4314595"   "4376657"   "4437922"   "4505759"   "4548654"   "4851358"   "4868133"   "5024723"   "5189500"   "5194395"   "5327007"   "5374564"   "5401669"   "5403406"   "5436175"   "5445975"   "5478408"   "5502010"   "5502331"   "5508207"   "5534294"   "5539245"   "5593494"   "5611855"   "5674756"   "5738942"   "5788763"   "5882987"   "5939770"   "5944889"   "5954873"   "5994761"   "6180220"   "6190631"   "6191010"   "6204152"   "6221743"   "6236104"   "6245645"   "6284384"   "6306733"   "6336968"   "6339016"   "6361619"   "6432197"   "6485807"   "6503594"   "6537368"   "6537655"   "6544656"   "6579779"   "6586068"   "6666915"   "6669777"   "6673147"   "6897084").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/13 10:57
L8	1	"20050253221"	US-PGPUB; USPAT; USOCR	OR	ON	2007/07/13 10:57
L9	2	(large or high) near (resistance or resistivity) near4 (silicon or si) near (substrate or wafer) and (seco or secco) near2 (etching)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 12:31
L10	13	(large or high) near (resistance or resistivity) near4 (silicon or si) near (substrate or wafer) and (bmd or oxygen near2 precipitat\$3 or bulk adj microdefect or bulk adj micro adj defect) near5 (size or radius or diameter or microns or micrometers or nm or nanometers)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 11:23
L12	21	(large or high) near (resistance or resistivity) near4 (silicon or si) near (substrate or wafer) and (oxygen) near4 (density or concentration) and (carbon) near4 (density or concentration)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 11:28

## EAST Search History

L13	2	"20030068890"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 11:28
L14	18	(rf or radio adj frequency or high adj frequency or microwave) near4 (silicon or si) near (substrate or wafer) and (bmd or oxygen near2 precipitat\$3 or bulk adj microdefect or bulk adj micro adj defect)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 12:11
L15	25	(rf or radio adj frequency or high adj frequency or microwave) near4 (silicon or si) near (substrate or wafer) and carbon near2 (concentration or density)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 12:31
L16	8	(large or high) near (resistance or resistivity) near4 (silicon or si) near (substrate or wafer) and (seco or secco)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 12:43
S2	7	"6858094".pn. "20040005777".pn. "6544656".pn. "5502331".pn.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/13 08:35
S3	4100	438/17.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 16:18
S4	198	438/17.ccls. and (silicon or wafer) near6 (resistivity or resistance or (defect or dislocation or bmd or precipitate) near2 (density or concentration))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 16:23

## EAST Search History

S5	157	438/143.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 17:02
S6	.80	438/402.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 17:25
S7	493	438/471.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 17:33
S8	251	438/799.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 17:46
S9	158	257/610.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 17:57
S10	148	257/611.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 18:04
S11	136	257/612.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 18:06

## EAST Search History

S12	526	257/655.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/12 18:06
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